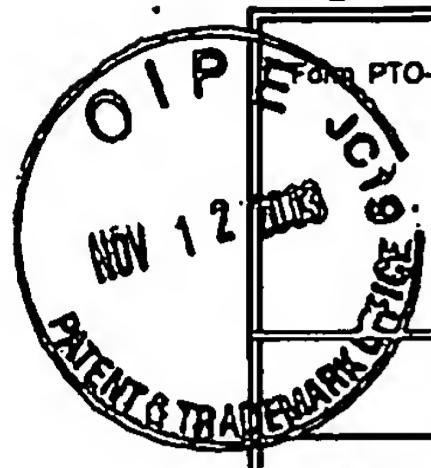


1/1 IDS 7/21/03

ID/624716

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				ATTY. DOCKET NO. M122-2357		priority SERIAL NO. 10/364,054			
				APPLICANT Luan C. Tran					
				priority FILING DATE February 10, 2003		priority GROUP 2812			
U.S. PATENT DOCUMENTS									
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate	
QH	AA	6,458,666 B2	10-2002	Wasshuber					
QH	AB	6,444,548 B2	09-2002	Divakaruni et al.					
QH	AC	3,886,003	05-1975	Takagi et al.					
QH	AD	4,366,338	12-1982	Turner et al.					
QH	AE	6,008,115	12-1999	Jung					
QH	AF	6,506,647 B2	01-2003	Kuroda et al.					
QH	AG	US2001/0036713A1	11-01-2001	Rodder et al.				July 5, 2001	
QH	AH	US2002/0034865A1	03-21-2002	Umimoto et al.				Nov. 30, 2001	
QH	AI	09/876,722		Scott				June 6, 2001	
QH	AJ	10/133,193		McQueen et al.				April 26, 2002	
	AK								
	AL								
FOREIGN PATENT DOCUMENTS									
		Document Number	Date	Country		Class	Subclass	Translation	
								Yes	No
	AM								
	AN								
	AO								
	AP								
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)									
QH	AQ		Young et al., "A 0.13 μ m CMOS Technology with 193 nm Lithography and Cu/Low-k for High Performance Applications", IEDM, pgs. 563-566, April 2000.						
QH	AR		Yeh et al., "Optimum Halo Structure for Sub-0.1 μ m CMOSFETs", IEEE Transactions on Electronic Devices, Vol. 48, No. 10, October 2001, pgs. 2357-2362.						
QH	AS		Bouillon et al., "Re-examination of Indium implantation for a low power 0.1 μ m technology", IDEM, pgs. 897-900, 1995 (year is sufficient so that date is not in issue).						
EXAMINER			DATE CONSIDERED						
<i>James M. Kennedy</i>			Feb 15, 2005						
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									

1/3 IDS 11/12/03



U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				ATTY. DOCKET NO. MI22-2357	SERIAL NO. 10/624,716		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Luan C. Tran			
				FILING DATE July 21, 2003	GROUP 2812		
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
QH	AA	6,144,079 A	11-2000	Shirahata et al.			
QH	AB	6,033,952	03-2000	Yasumura, et al.			
QH	AC	6,124,168	09-2000	Ong			
QH	AD	5,688,705	11-1997	Bergemann			
QH	AE	5,866,448	02-1999	Pradeep et al.			
QH	AF	5,858,847	01-1999	Zhou et al.			
QH	AG	6,380,598	04-2002	Chan			
QH	AH	6,060,364	05-2000	Maszara et al.			
QH	AI	6,194,276 B1	02-2001	Chan et al.			
QH	AJ	6,359,319 B1	03-2002	Noda			
QH	AK	5,164,806	11-1992	Nagatomo et al.			
QH	AL	4,937,756	06-1990	Hsu et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
QH	AM	EP 0718881	06/96	EPO, Chan			Yes
	AN						No
	AO						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
QH	AR	Watanabe, H. et al., Novel $0.44\mu\text{m}^2$ Ti-Silicide STI Cell Technology for High-Density NOR Flash Memories and High Performance Embedded Application, IEEE 1998, pp. 38.2.1 - 38.2.4.					
QH	AS	Wolf, S., "Silicon Processing for the VLSI Era", Vol. 2, pp. 632-635.					
QH	AT	MITSUBISHI ELECTRIC WEBSITE: Reprinted from website http://www.mitsubishielectric.com/r_and_d/tech_showcase/ta8.php on 3/29/2001: "8. Production Line Application of a Fine Hole Pattern-Formation Technology for Semiconductors", on 3/29/2001, 4 pgs					
EXAMINER		DATE CONSIDERED					
Jennifer M. Kennedy		Feb. 15, 2005					
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2357	SERIAL NO. 10/624,716		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT Luan C. Tran					
		FILING DATE July 21, 2003		GROUP 2812			
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
QH	AA	5,930,614	07-1999	Eimori et al.			
QH	AB	5,635,744	06-1997	Hidaka et al.			
QH	AC	6,204,536	03-2001	Maeda et al.			
QH	AD	6,515,899 B1	02-2003	Tu et al.			
QH	AE	4,570,331	02-1986	Eaton, Jr. et al.			
QH	AF	6,429,079 B1	08-2002	Maeda et al.			
QH	AG	6,607,979 B1	08-2003	Kamiyama			
QH	AH	4,686,000	08-1987	Heath			
QH	AI	5,814,875	09-1998	Kumazaki			
QH	AJ	5,654,573	08-1997	Oashi et al.			
QH	AK	6,479,330 B2	11-2002	Iwamatsu et al.			
QH	AL	6,586,803	07-2003	Hidaka et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
	AM						Yes
	AN						No
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
QH	AR	CAHNERS SEMICONDUCTOR INTERNATIONAL WEBSITE: Reprinted from http://www.semiconductor.net/semiconductor/issues/1999/sep99/docs/feature1.asp on 3/29/2001: "Resists Join the Sub-λ Revolution", 9 pgs.					
QH	AS	CAHNERS SEMICONDUCTOR INTERNATIONAL WEBSITE: Reprinted from http://www.semiconductor.net/semiconductor/issues/1999/aug99/docs/lithography.asp on 3/29/2001: "Paths to Smaller Features", 1 pg.					
QH	AT	Wolf, S., "Silicon Processing for the VLSI Era, Vol. 1: Process Technology," Lattice Press 1986, pp. 434-437.					
EXAMINER			DATE CONSIDERED				
<i>James M. Kennedy</i>			<i>Feb 15, 2005</i>				
*EXAMINER Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

3/3 IDS 11/12/03

<p style="text-align: center;">U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE</p> <p style="text-align: center;">LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)</p>				ATTY. DOCKET NO. MI22-2357		SERIAL NO. 10/624,716	
				APPLICANT Luan C. Tran			
				FILING DATE July 21, 2003		GROUP 2812	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
QH	AA	6,552,401 B1	04-2003	Dennison			
QH	AB	6,627,524 B2	09-2003	Scott			
QH	AC	US2002/0182829A1	12-2002	Chen			
QH	AD	US2002/0164846A1	11-2002	Lin et al.			Apr. 19, 2002
QH	AE	US2003/0071310A1	04-2003	Salling et al.			Oct. 11, 2001
	AF						
	AG						
	AH						
	AI						
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	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
	AM						Yes
	AN						No
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
M	AR		<p><i>"Session 18: Integrated Circuits and Manufacturing - DRAM and Embedded DRAM Technology," 2001 IEDM Technical Program, 2001 IEEE International Electron Devices Meeting, Dec. 4, 2001, reprinted 11/15/01 from http://www.his.com/~iedm/techprogram/sessions/s18.html, pp. 1-2.</i></p>				
Q	AS						
	AT						
EXAMINER		DATE CONSIDERED					
<i>Jeffrey M. Kennedy</i>		<i>Feb 15 2005</i>					
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MAR-10-2004 13:49

WELLS ST. JOHN, P.S.

5098383424 P.03/03

IDS 3/10/04

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2357	SERIAL NO. 1M74716		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Luan C. Tran			
				PILING DATE July 31, 2003	GROUP 2811		
U.S. PATENT DOCUMENTS							
*EXAMINER INITIALS		Document Number	Date	Name	Class	Subclass	Filing Date If Applicable
QH	AA	6,521,487 B1	02-2003	Chen et al.			
QH	AB	6,492,694 B2	12-2002	Nohia et al.			
QH	AC	6,468,865 B1	10-2003	Yung et al.			
QH	AD	6,451,704 B1	09-2002	Pradeep et al.			
QH	AF	6,436,747 B1	08-2002	Sugama et al.			
QH	AF	6,362,034 B1	03-2002	Sandford et al.			
QH	AG	6,277,720 B1	08-2001	Umesh et al.			
QH	AH	5,923,973	07-1999	Roland			
QH	AI	5,866,934	02-1999	Kulath et al.			
QH	AJ	6,180,468 B1	01-2001	Yu et al.			
QH	AK	6,207,510 B1	03-2001	Abcini et al.			
QH	AL	US2003/01130112A1	02-2003	Wada et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation Yes No
AM							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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	AS						
	AT						
EXAMINED	<i>Jennifer M. Kennedy</i>			DATE CONSIDERED	Feb 13, 2005		
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

1, IDS 4/16/04

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WELLS ST. JOHN, P.S.

5098383424 P. 03/03

Sheet 1 of 1

Form PTO-1499		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. N022-2357	SERIAL NO. 10624.716		
LIST OF ART CITED BY APPLICANT (List serials of (if necessary)				APPLICANT Lam C. Tran			
				FILING DATE July 21, 2003	GROUP 2011		
U.S. PATENT DOCUMENTS							
*Examiner Initials		Document Number	Date	Name	Class	Subclass	Filing Date if appropriate
QH	AA	5,841,785	11-1998	Ishikawa			
QH	AB	6,331,458 D1	12-2001	Anjum et al.			
QH	AC	6,251,744 D1	06-2001	Su et al.			
	AD						
	AE						
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	AG						
	AH						
	AI						
	AJ						
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	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation Yes No
	AN						
	AN						
	AO						
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	AU						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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EXAMINER		DATE CONSIDERED		Signature			
*EXAMINER Initial if reference considered, whether or not citation is in conformance with 37 CFR 1.96; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

1/1 IDS 11/1/04

NOV-01-2004 16:10

WELLS ST. JOHN, P.S.

5098383424 P.03/03

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE					ATTY. DOCKET NO. M22-2357	SERIAL NO. 10524.716	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Luan C. Tran		
					FILING DATE July 21, 2003	GROUP 2811	
U.S. PATENT DOCUMENTS							
Reference Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
<i>QH</i>	AA	3,767,557	06-1993	Kizilyalli			
<i>QH</i>	AB	3,369,293	11-1994	Vinal			
<i>QH</i>	AC	3,397,017	03-1995	Moskhi			
<i>QH</i>	AD	3,873,728	04-1999	Illikku			
<i>QH</i>	AE	3,672,526	09-1997	Kawamura			
<i>QH</i>	AF	3,725,714	07-1993	Wakamatsu et al.			
<i>QH</i>	AG	3,440,161	08-1995	Iwamatsu et al.			
<i>QH</i>	AH	5,355,012	10-1994	Yamaguchi et al.			
<i>QH</i>	AI	3,830,226	01-1999	Wu			
<i>QH</i>	AJ	3,877,036	03-1999	Wu			
<i>QH</i>	AK	6,518,113 B1	11-2003	Buynoobi			
<i>QH</i>	AL	6,542,581 B2	11-2003	Mazuda et al.			
<i>QH</i>	AM	6,297,032 B1	10-2001	Lin et al.			
<i>QH</i>	AN	US2002/0043692A1	04-2002	Maeda et al.			
<i>QH</i>	AO	US2003/0189231	10-2003	Clavenger et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation Yes No
	AP						
	AO						
	AR						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)							
	AS						
	AT						
EXAMINER	<i>Jennifer M. Kennedy</i>			DATE CONSIDERED	<i>Feb 15 2005</i>		
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 409; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.</small>							